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Xiao-Cong Yuan
P. Scott Carney
Kebin Shi
Michael G. Somekh
Editors

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Contents

vii	Authors
ix	Symposium Committees
xiii	Conference Committee

SESSION 1 SUPER-RESOLUTION IMAGING

11186 03	Fluorescence optical super-resolution imaging of nitrogen-vacancy centers based on saturated competition microscopy [11186-2]
11186 05	High-resolution reconstruction method of segmented planar imaging based on compressed sensing [11186-4]
11186 06	Improved microsphere-assisted super-resolution imaging by plasmon coupling [11186-31]

SESSION 2 LABEL-FREE IMAGING I

11186 07	Hole-array spatial light modulation for single-pixel imaging (Invited Paper) [11186-5]
----------	---

SESSION 3 TOMOGRAPHIC IMAGING AND SUPER-RESOLUTION IMAGING

11186 0D	Label-free Rheinberg staining of cells using digital holographic microscopy and spatial light interference microscopy [11186-10]
11186 0E	A tunable 3D optical diffraction tomography system with high measurement accuracy [11186-11]
11186 0F	Video-rate isotropic quantitative differential phase contrast microscopy based on color-multiplexed annular illumination [11186-12]

SESSION 4 LABEL-FREE IMAGING II

11186 0J	Machine-learning enhanced photoacoustic computed tomography in a limited view configuration [11186-18]
11186 0N	Multicolor stimulated Raman and fluorescence imaging for investigating lipid metabolism [11186-22]

SESSION 5 IMAGING TECHNOLOGIES I

- 11186 00 **Three-dimensional macro-scale micro-structure imaging with deep ultraviolet excitation (Invited Paper) [11186-23]**

SESSION 6 IMAGING TECHNOLOGIES II

- 11186 0T **Structured illumination microscopy with modified joint Richardson-Lucy deconvolution [11186-28]**

POSTER SESSION

- 11186 0Y **High-speed in vitro intensity diffraction tomography [11186-33]**
- 11186 10 **A method of image restoration technology based on parallel phase diversity algorithm [11186-35]**
- 11186 11 **Nonlinear focal modulation microscopy based on interleaved reconstruction [11186-36]**
- 11186 12 **Propagation of ultrasound-modulated scattered light in biological tissue by using COMSOL multiphysics [11186-37]**
- 11186 13 **Super-resolution hyperspectral compressed sampling imaging by push-broom coded aperture [11186-38]**
- 11186 14 **A method of Fourier ptychography based on variable aperture scanning [11186-39]**
- 11186 15 **Influence of spatial power spectrum pattern gray-level distortion on coherent diffraction imaging reconstruction [11186-40]**
- 11186 16 **Axial resolution enhancement in light sheet microscopy using mode modulation [11186-41]**
- 11186 17 **Analysis of encoding aperture processing error for optical field modulation of compressed sampling spectrum imaging [11186-42]**
- 11186 18 **Multi-region processing method for single image deraining [11186-43]**
- 11186 1A **Optical-phase modulator based on stacked piezoelectric ceramics [11186-45]**
- 11186 1B **Frequency shifting confocal microscopy via azimuthally polarized Bessel-Gaussian beam [11186-46]**
- 11186 1D **Research progress of coronary artery calcification based on optical coherence tomography [11186-48]**

- 11186 1F **Measuring the nano-mechanical properties of normal and cancerous prostate cells using atomic force microscopy** [11186-50]
- 11186 1G **Methods on adaptive identification with space light modulate** [11186-51]
- 11186 1H **Numerical investigation of photonic nanojets generated from D-shaped dielectric microfibers** [11186-52]
- 11186 1K **Quantitative phase microscopy based on color-multiplexed single-shot Fourier ptychography** [11186-56]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Artur, Camille, 0O	Liu, Xu, 03
Bandyopadhyay, Sankhyabrata, 1H	Liu, Yana, 1D
Cai, Chuangjian, 0J	Liu, Yong, 1B
Cao, Shuo, 0E	Liu, Zhongwei, 10
Cao, Yurong, 06	Luo, Jianwen, 0J
Chen, Huasong, 18	Luo, Jintao, 0T
Chen, Jiabi, 0E	Lv, Xing, 0E
Chen, Mengdan, 1F	Ma, Cheng, 0J
Chen, Qian, 0F, 0Y, 1K	Matlock, Alex, 0Y
Chen, Tao, 1A	Mayerich, David, 0O
Chen, Yuchen, 11, 16	Meng, Haoran, 05
Deng, Handi, 0J	Oda, Robert, 0N
Ding, Can, 05	O'Dwyer, Kevin, 0D
Ding, Qin, 18	Ozeki, Yasuyuki, 0N
Ding, Tianxin, 1A	Pan, Jinghan, 14, 17
Eriksen, Jason, 0O	Pan, Xiangpeng, 0F
Fan, Xin, 0D	Peng, Dongqing, 12
Fan, Yao, 0F	Peng, Zeng, 1H
Fan, Yuanyuan, 18	Qi, Junli, 13, 14, 15, 17
Feng, Jiansong, 1H	Qi, Peiliang, 12
Fu, Meicheng, 14, 17	Qiang, Hao, 18
Gu, Guoqiang, 1H	Qin, Na, 1D
Guo, Jiaming, 0O	Ruan, Weiwei, 1F
Guo, Yanfang, 13, 14, 15, 17	Sato, Ryo, 07
Hayasaki, Yoshio, 07	Shao, Liyang, 1H
Healy, John J., 0D	Shen, Xingliang, 1H
Hennelly, Bryan M., 0D	Shou, Jingwen, 0N
Huang, Lin, 1D	Song, Haiyang, 12
Ito, Yujiro, 07	Sun, Jiasong, 0F, 1K
Jiang, Lianxiang, 10	Tang, Wusheng, 13, 14, 15, 17
Jiang, Yupeng, 10	Tang, Zhengyuan, 0D
Kong, Meimei, 1A	Tian, Lei, 0Y
Kuang, Cuifang, 03, 0T, 11, 16, 1B	Wang, Bin, 10
Li, Chuankang, 03	Wang, Guanghui, 0E
Li, Feiyan, 1A	Wang, Jianguo, 06
Li, Jiaji, 0Y	Wang, Jingbo, 1D
Li, Mengzhu, 13, 15, 17	Wang, Wei, 13, 15
Li, Mi, 0E	Wang, Weizheng, 13
Li, Mingsuo, 1G	Wang, Xiaochun, 14, 17
Li, Qin, 1D	Wang, Xiaofeng, 15
Li, Xiujian, 13, 14, 15, 17	Wang, Xuanhao, 0J
Li, Yuhang, 03	Wang, Yuhua, 1F
Li, Yunzhe, 0Y	Wu, Chebin, 1A
Liang, Zhongcheng, 1A	Xiao, Dongrui, 1H
Liu, Danni, 1D	Xu, Liu, 0T, 16
Liu, Hua, 1G	Xu, Min, 05
Liu, Jiying, 13	Xu, Zhengxiang, 1A
Liu, Minshi, 10	Yang, Hongqin, 1F
Liu, Xinyue, 05	Yang, Songlin, 06

Yang, Xinfeng, 1H
Ye, Yong-Hong, 06
Yi, Wenjun, 13, 14, 15, 17
Zeng, Jinshu, 1F
Zhang, Chengfeng, 11, 16
Zhang, Xiangchao, 05
Zhang, Xiaoman, 12
Zhang, Yasong, 18
Zhao, Rui, 1A
Zhou, Liwei, 1G
Zhu, Jubo, 13, 14, 15, 17
Zhu, Lili, 12
Zhu, Mengjun, 13, 14, 15, 17
Zhu, Ronggang, 1G
Zuo, Chao, 0F, 0Y, 1K

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- 4 Label-Free Imaging II
Xiao-Cong Yuan, Shenzhen University (China)
- 5 Imaging Technologies I
Kebin Shi, Peking University (China)
- 6 Imaging Technologies II
Xiao-Cong Yuan, Shenzhen University (China)